

# Layering of [BMIM]<sup>+</sup>-based ionic liquids at a charged sapphire interface

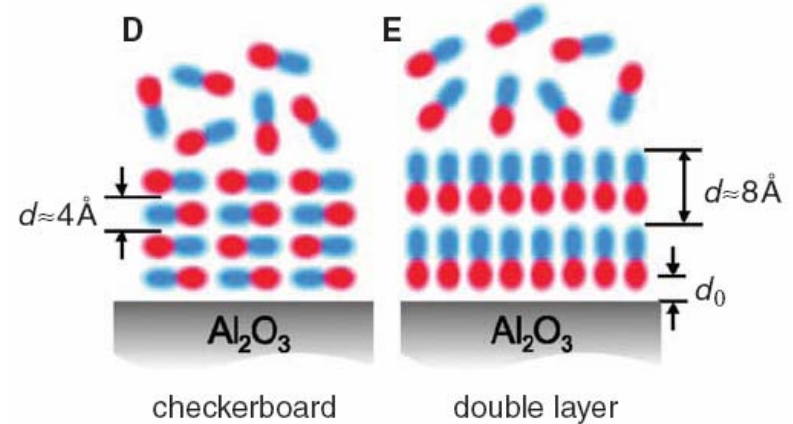
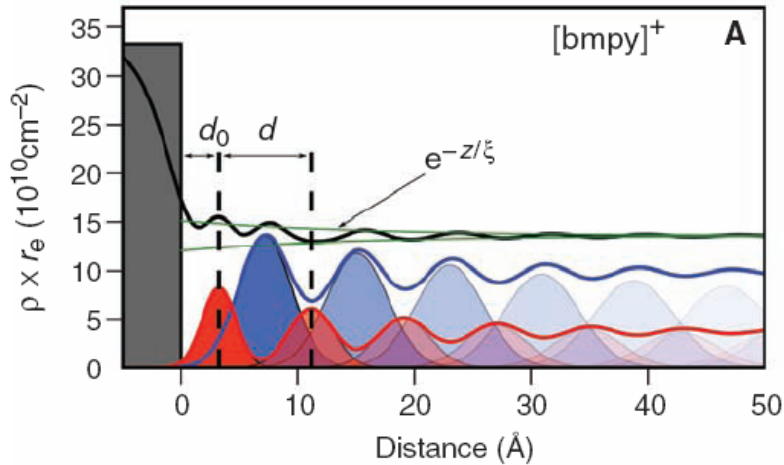
M. Mezger et al., *J. Chem. Phys.* **131**, 094701 (2009)

presenter : Yoonnam Jeon (30th Dec. 2009)

# Introduction

Mezger et al., Science **322**, 424 (2008)

stack in alternately charged layers ([C<sub>n</sub>MIM][FAP])

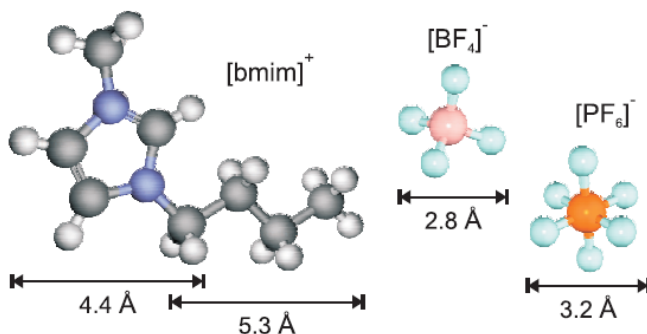


- [BMIM][PF<sub>6</sub>] : strong alternate-charge layering
- [BMIM][BF<sub>4</sub>] : only a single dense layer

alternate-charge layering : not a universal characteristic of all ILs  
dichotomy for two ILs : from the differences in the bulk correlations

# Samples

## Ionic liquids



high purity (from Merck)



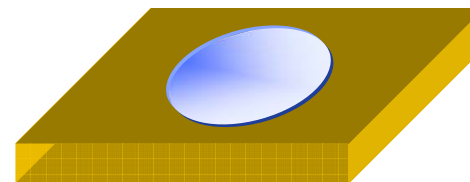
baked out at 80°C  
in a vacuum (~12 h)



10  $\mu$ l drop

## substrate

irradiated by UV light in an oxygen  
atmosphere for 30 min.

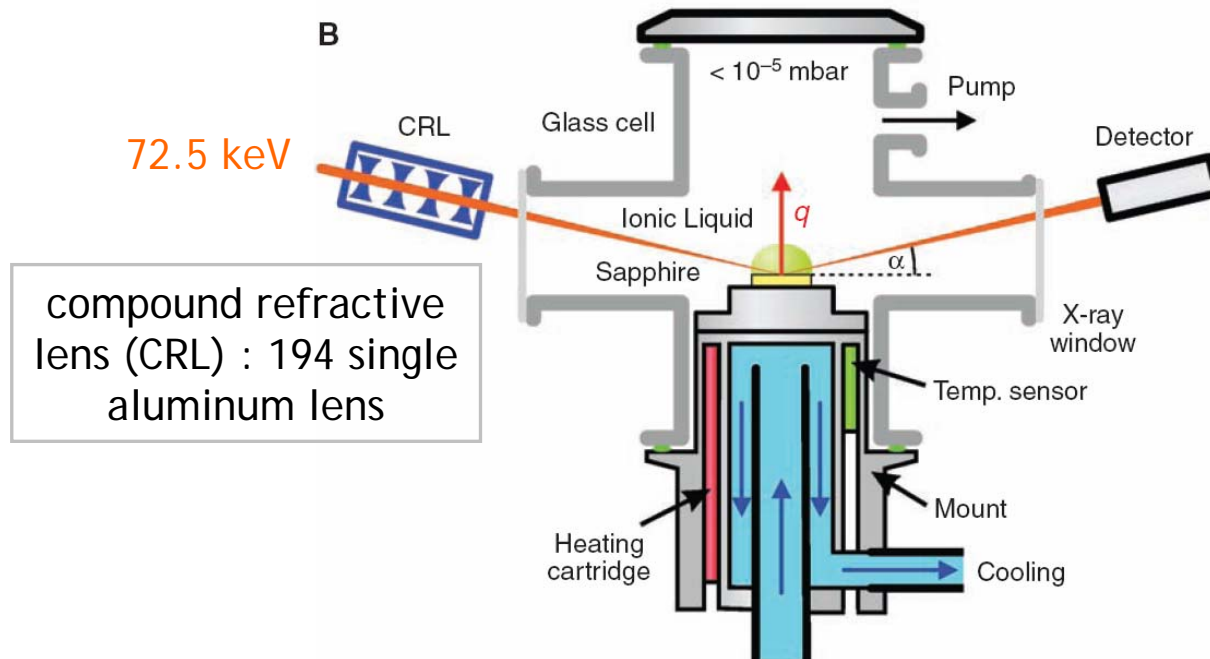


(0001) sapphire wafer (t~400  $\mu$ m)

# Experiments

- X-ray reflectivity
- Kelvin probe  
substrate : surface charge is negative (-550 mV)
- Bulk liquid scattering  
detector : 2D image plate
- Interfacial tension  
air/ILs & hexane/ILs (at 22 °C, 22 % relative humidity)

# Experimental setup

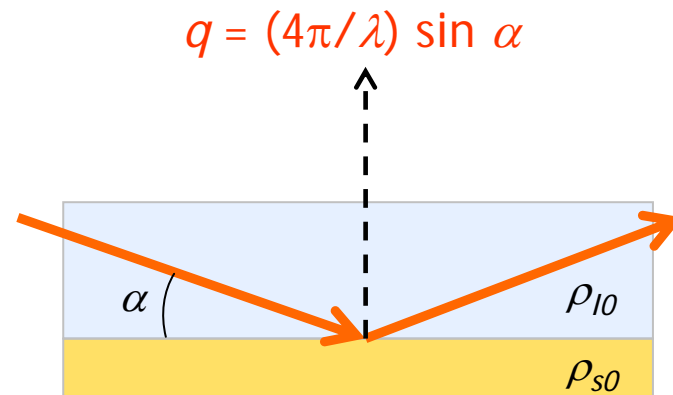


footprint on the sample  $\sim 6 \times 25 \mu\text{m}^2$

# Theory of reflectivity

for  $q > 4q_c$

$$R(q) = \frac{R_F(q)}{(\rho_{s0} - \rho_{l0})} \left| \int \frac{d\rho(z)}{d\rho} e^{iqz} dz \right|^2$$



where  $R_F(q) = \left| \frac{q - \sqrt{q^2 - q_c^2}}{q + \sqrt{q^2 - q_c^2}} \right|^2$ ,

$$q_c \approx 4\sqrt{\pi r_e (\rho_{s0} - \rho_{l0})}$$

$r_e$  classical electron radius

# Surface layering models

$$R(q) = \frac{R_F(q)}{(\rho_{s0} - \rho_{l0})} \left| \int \frac{d\rho(z)}{d\rho} e^{iqz} dz \right|^2$$

## Lorentzian model (LM)

$$\rho(z) = \rho_s(z) + \rho_l(z - d_0)$$

$$\left[ \begin{array}{l} \rho_s(z) = \frac{\rho_{s0}}{2} \left[ 1 - \operatorname{erf} \left( \frac{z}{\sqrt{2}\sigma} \right) \right], \\ \rho_l(z) = \rho_{l0} \Theta(z) \left[ 1 + A \exp \left( -\frac{z}{\xi} \right) \sin \left( \frac{2\pi z}{d} \right) \right] \end{array} \right.$$

$\sigma$  : roughness width

$\Theta$  : heaviside step function

A : amplitude

$\xi$  : decay length

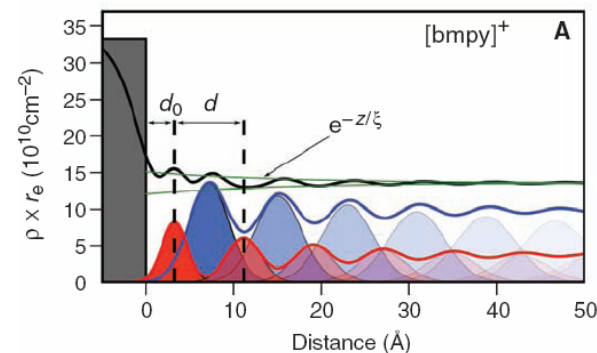
d : periodicity

## Distorted crystal (DC) model

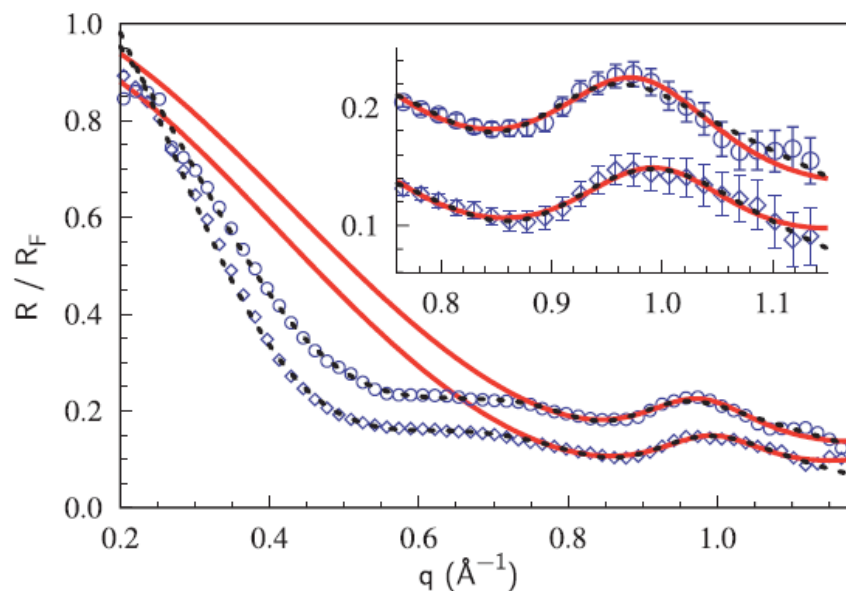
$$\rho(z) = \rho_s(z) + (2\pi)^{-1} \sum_{n=0}^{\infty} \rho_n(z - d_0)$$

$$\left[ \rho_n(z) = \frac{\rho_c}{\sigma_n^c} e^{-\frac{1}{2} \left( \frac{nd-z}{\sigma_n^c} \right)^2} + \frac{\rho_a}{\sigma_n^a} e^{-\frac{1}{2} \left( \frac{(n+\varepsilon)d-z}{\sigma_n^a} \right)^2} \right.$$

(employed originally to describe surface-induced, exponentially decaying layering at liquid metal surfaces)

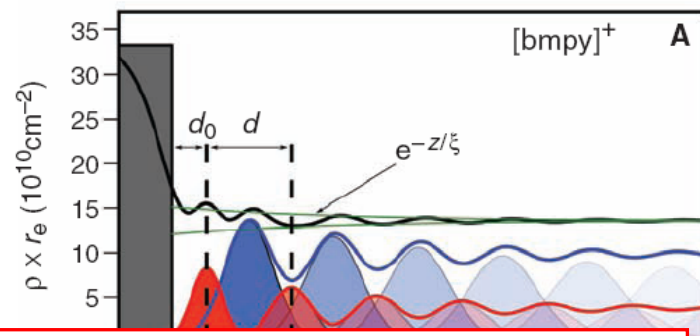


# Surface layering of [BMIM][PF<sub>6</sub>]



- : 110 °C [BMIM][PF<sub>6</sub>]
- ◇ : 5 °C [BMIM][PF<sub>6</sub>]
- ... : fit with DC model
- : fit with LM

	LM		DC	
	10 °C	110 °C	10 °C	110 °C
$d(\text{Å})$	$6.3 \pm 0.1$	$6.5 \pm 0.2$	$6.5$	$6.9$
$\xi$	$1.5 \pm 0.2$	$1.4 \pm 0.1$	1.2	1.5
$\sigma(\text{Å})$	$1.4 \pm 0.1$	$1.4 \pm 0.1$	2.9	2.5
$d/d_0$	$0.1 \pm 0.1$	$0.0 \pm 0.1$	0.5	0.5

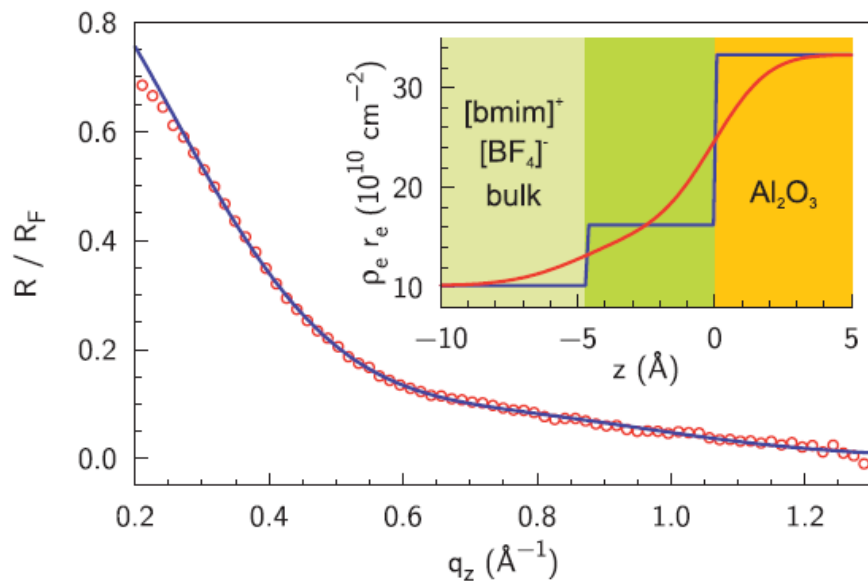


Equally good fits could be obtained assuming either a first cation layer or a first anion layer

: contrast to the [FAP]<sup>-</sup> based RTILs



# Single layer of [BMIM][BF<sub>4</sub>]



○ : 110 °C [BMIM][BF<sub>4</sub>]

— : fit

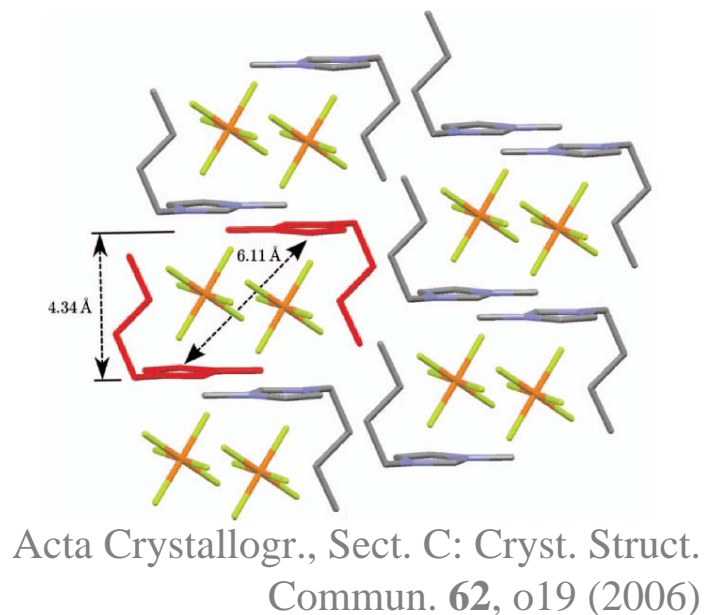
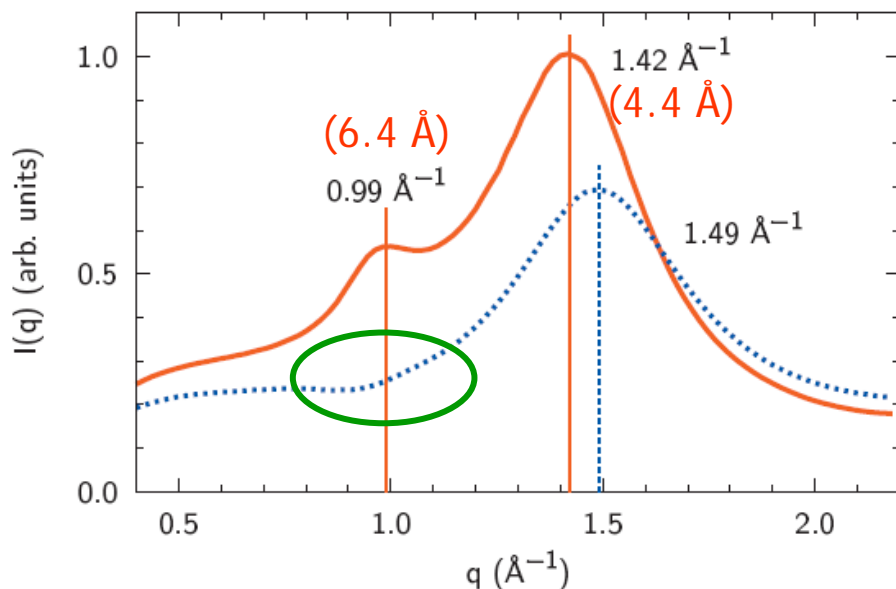
Layer	$l$ (Å)	$\sigma$ (Å)	$\rho$ (g cm <sup>-3</sup> )	$\rho_e r_e$ (10 <sup>15</sup> m <sup>-2</sup> )
RTIL (bulk)	...	2.1	1.15	1.02
RTIL (IFL)	4.65	1.6	1.84	1.63
Al <sub>2</sub> O <sub>3</sub> (bulk)	...	...	4.00	3.33

no temp. dependence

absence of any distinct features at  $R/R_F$

single slab layer with ~60% enhanced ED

# Bulk liquid scattering



first peak corresponding to the length scale of  $6 \text{ \AA}$

: should be attributed mostly to interionic correlations between ions absent in  $[\text{BMIM}][\text{BF}_4]$  (**anion-anion**)



bulk peak related to the double layer periodicity in  $[\text{BMIM}][\text{PF}_6]$  is missing in the bulk liquid diffraction pattern of  $[\text{BMIM}][\text{BF}_4]$